

Notice of References Cited	Application/Control No. 10/754,389	Applicant(s)/Patent Under Reexamination HAN ET AL.	
	Examiner Nathan W. Ha	Art Unit 2814	Page 1 of 1

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	C	US-6,774,405 B2	08-2004	Yasukawa et al.	257/99
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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